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1. REPORT DATE (DD-MM-YYYY) 28-08-2018		2. REPORT TYPE Final Report		3. DATES COVERED (From - To) 1-May-2016 - 31-Jan-2017	
4. TITLE AND SUBTITLE Final Report: SHORT-TERM INNOVATIVE RESEARCH (STIR) PROGRAM:"Synthesizing new functional 2D semiconducting solids"			5a. CONTRACT NUMBER W911NF-16-1-0186		
			5b. GRANT NUMBER		
			5c. PROGRAM ELEMENT NUMBER 611102		
6. AUTHORS			5d. PROJECT NUMBER		
			5e. TASK NUMBER		
			5f. WORK UNIT NUMBER		
7. PERFORMING ORGANIZATION NAMES AND ADDRESSES University of Kentucky 500 South Limestone Street 109 Kinkead Hall Lexington, KY 40526 -0001			8. PERFORMING ORGANIZATION REPORT NUMBER		
9. SPONSORING/MONITORING AGENCY NAME(S) AND ADDRESS (ES) U.S. Army Research Office P.O. Box 12211 Research Triangle Park, NC 27709-2211			10. SPONSOR/MONITOR'S ACRONYM(S) ARO		
			11. SPONSOR/MONITOR'S REPORT NUMBER(S) 69060-MS-II.2		
12. DISTRIBUTION AVAILABILITY STATEMENT Approved for public release; distribution is unlimited.					
13. SUPPLEMENTARY NOTES The views, opinions and/or findings contained in this report are those of the author(s) and should not be construed as an official Department of the Army position, policy or decision, unless so designated by other documentation.					
14. ABSTRACT					
15. SUBJECT TERMS					
16. SECURITY CLASSIFICATION OF:			17. LIMITATION OF ABSTRACT UU	15. NUMBER OF PAGES	19a. NAME OF RESPONSIBLE PERSON Madhusudan Menon
a. REPORT UU	b. ABSTRACT UU	c. THIS PAGE UU			19b. TELEPHONE NUMBER 859-549-4297

**RPPR Final Report**  
as of 17-Sep-2018

Agency Code:

Proposal Number: 69060MSII

**Agreement Number: W911NF-16-1-0186**

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EIN: 616033693

**Report Date:** 30-Apr-2017

Date Received: 28-Aug-2018

**Final Report** for Period Beginning 01-May-2016 and Ending 31-Jan-2017

**Title:** SHORT-TERM INNOVATIVE RESEARCH (STIR) PROGRAM:"Synthesizing new functional 2D semiconducting solids"

**Begin Performance Period:** 01-May-2016

**End Performance Period:** 31-Jan-2017

**Report Term:** 0-Other

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**Distribution Statement:** 1-Approved for public release; distribution is unlimited.

**STEM Degrees:** 2

**STEM Participants:** 0

**Major Goals:** Experimental synthesis of a new class of 2D material that is one atom thick and flat following the theoretical guidance as part of the exploratory research.

**Accomplishments:** We attempted the growth of 2D SiC on polycrystalline copper rolls using our Chemical Vapor Deposition (CVD) reactor. During the growth process, both CH<sub>4</sub> and SiH<sub>4</sub> gases were introduced. The specific objective was to create a stable isolated single layer of the SiC material. The Raman spectrum of the sample grown on copper roll at 1000 C with combined flows of CH<sub>4</sub> and SiH<sub>4</sub> were analyzed. The TEM images confirmed the presence of both C and Si. Most interestingly, Raman spectrum showed SiC like features in the peaks. These results are significant and confirm growth of at least regions of 2D SiC structures.

**Training Opportunities:** Graduate students were involved in the experimental effort performing Raman studies.

**Results Dissemination:** Nothing to Report

**Honors and Awards:** Nothing to Report

**Protocol Activity Status:**

**Technology Transfer:** Nothing to Report

**PARTICIPANTS:**

**Participant Type:** Faculty

**Participant:** Mahendra Sunkara Prof

**Person Months Worked:** 1.00

**Funding Support:**

Project Contribution:

International Collaboration:

International Travel:

National Academy Member: N

Other Collaborators:

**RPPR Final Report**  
as of 17-Sep-2018

**Participant Type:** Graduate Student (research assistant)

**Participant:** Rong Zhao

**Person Months Worked:** 6.00

**Funding Support:**

Project Contribution:

International Collaboration:

International Travel:

National Academy Member: N

Other Collaborators:

**Participant Type:** Graduate Student (research assistant)

**Participant:** Daniel Jaramillo

**Person Months Worked:** 6.00

**Funding Support:**

Project Contribution:

International Collaboration:

International Travel:

National Academy Member: N

Other Collaborators:

**ARTICLES:**

**Publication Type:** Journal Article

Peer Reviewed: Y

**Publication Status:** 5-Submitted

**Journal:** Physical Review B

Publication Identifier Type:

Publication Identifier:

Volume:

Issue:

First Page #:

Date Submitted:

Date Published:

Publication Location:

**Article Title:** Structural, electronic and mechanical properties of Si<sub>2</sub>BN under uniaxial strain: an ab-initio study'

**Authors:** Z. G. Fthenakis and M. Menon

**Keywords:** nanomechanics, molecular dynamics, first principles calculations

**Abstract:** Si<sub>2</sub>BN has been recently predicted theoretically as a new entirely planar 2-dimensional metallic material which is stable even at T> 1000 K. It was also found that it is metallic, with few states at the Fermi level and similar electronic properties at the Fermi level as silicene. In the present work we study its structural, electronic and mechanical properties under tensile strain till the fracture limit and compare them to the corresponding properties for graphene. According to our findings, the metallic character of Si<sub>2</sub>BN is enhanced as a function of strain, since strain introduces several conduction states into the valence band. Study of its mechanical properties reveals Si<sub>2</sub>BN to be anisotropic, while exhibiting large values of Young's modulus. Furthermore, structurally it is found to be very robust and comparable to graphene.

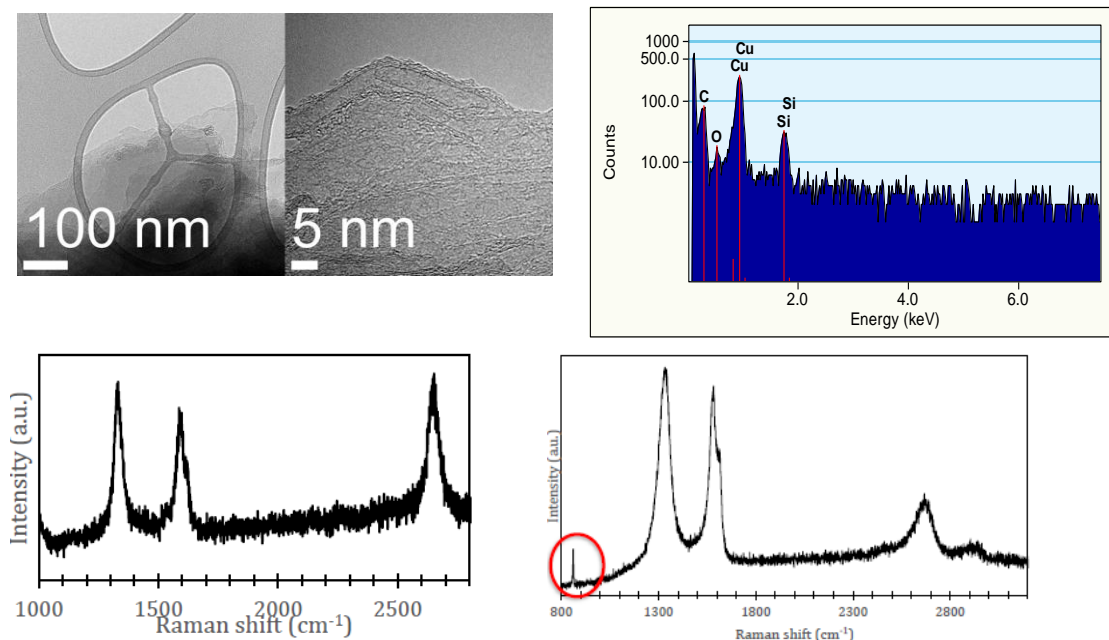
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Acknowledged Federal Support: Y

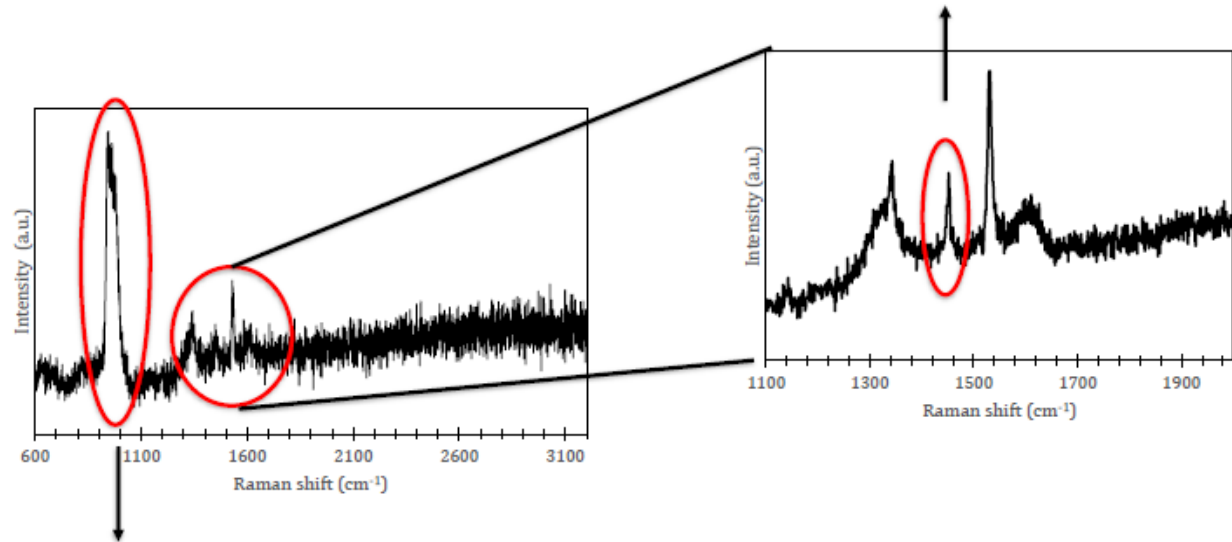


**FIGURE 1.** CVD system used for growth of 2D SiC

We have attempted growth of 2D SiC on polycrystalline copper foils using our Chemical Vapor Deposition (CVD) reactor as shown in Fig. 1. During the growth process, both  $\text{CH}_4$  and  $\text{SiH}_4$  gasses were introduced after annealing the copper substrate in a  $\text{H}_2/\text{Ar}$  flow at  $1000^\circ\text{C}$ . However, due to safety reasons and to facilitate slow growth rate, we have used very dilute  $\text{SiH}_4$  (2 mol. %) in hydrogen. This imposed the restriction of using low concentrations of methane. Our preliminary results showed formation of graphene at ultra-low concentration of methane ( $<0.5$  sccm compared to 20 sccm typically used for graphene synthesis). Since carbon solubility in copper is extremely low compared to that of Si, we maintained  $\text{SiH}_4$  throughout the cooling process even after the  $\text{CH}_4$  flow was turned off. Fig. 2 shows (a) low magnification TEM image (b) high magnification TEM image (c) EDX spectrum (d) Raman spectrum of the sample grown on copper foil at  $1000^\circ\text{C}$  with combined flows of  $\text{CH}_4$  and  $\text{SiH}_4$ . TEM images confirm the presence of layered structure while EDX confirms presence of both C and Si. Most interestingly, Raman spectrum shows SiC like feature ( $\sim 860\text{ cm}^{-1}$ ) in addition to typical D, G, and 2D peaks characteristic to graphene. These initial results are encouraging and confirms growth of at least regions of 2D SiC structures. We are planning to perform more in-depth characterization of the material and to reproduce the results.



**FIGURE 2.** Characterization results from preliminary 2D SiC synthesis experiments: (a) low magnification TEM image (b) high magnification TEM image (c) EDX spectrum (d) Raman spectra for samples with and without  $\text{SiH}_4$  showing SiC like peak in addition to graphene peaks when  $\text{SiH}_4$  is present.



**FIGURE 3.** Raman spectrum for a samples synthesized with CH<sub>4</sub> and SiH<sub>4</sub> showing additional peak between the D and G peaks of graphene.

Under varying conditions for CH<sub>4</sub> and SiH<sub>4</sub> residency times during the reduction, growth, and cooling processes we synthesized 2D materials which shows an additional Raman peak between D and G bands of graphene as shown in Fig. 3. Currently we are trying to understand the origin of this peak with additional characterizations.